

# Contents

Performance and Selection Criteria of Critical Components of STM and AFM . . . . .	1
<i>Y. Martin</i>	
Investigations on the SFM – Tip to Substrate Interaction . . . . .	11
<i>R. Kassing</i>	
New Scanning Microscopy Techniques: Scanning Noise Microscopy – Scanning Tunneling Microscopy Assisted by Surface Plasmons . . . . .	32
<i>R. Möller</i>	
An STM Study of the Oxygenation of Silicon . . . . .	49
<i>M.E. Welland, R.B. Leane</i>	
Scanning Near Field Optical Microscopy . . . . .	76
<i>U.Ch. Fischer</i>	
Study of Epitaxial Growth by Combination of STM and LEED . . . . .	85
<i>M. Henzler, U. Köhler, O. Jusko</i>	
STM Studies of Adsorbates in the Monolayer Range: Ag/Ni(100) and O/Ni(100) . . . . .	102
<i>A. Brodde, G. Wilhelmi, H. Neddermeyer</i>	
Molecular Imaging with the Scanning Tunneling Microscope . . . . .	117
<i>J.P. Rabe</i>	
Imaging of Magnetic Domains in Ferromagnets and Superconductors by Force and Tunneling Microscopy . . . . .	135
<i>U. Hartmann, R. Berthe, T. Göddenhenrich, H. Lemke, C. Heiden</i>	
Acoustic Microscopy: Pictures to Ponder . . . . .	153
<i>G.A.D. Briggs, R. Gundle, C.W. Lawrence, A. Rodriguez-Rey, C.B. Scruby</i>	
Real-Time Confocal Scanning Microscope – An Optical Instrument with a Better Depth Resolution . . . . .	167
<i>T. Sure</i>	

On the Search for Last Frontiers – Scanning Tunneling Microscopy and Related Techniques (Abstract) . . . . .	186
<i>D.W. Pohl</i>	
STM and AFM Extensions (Abstract) . . . . .	187
<i>H.K. Wickramasinghe</i>	
Bibliography . . . . .	189
<i>G.W.B. Schlüter</i>	